

Type	Hits	Search Text	DBs	Time Stamp	Comments
1	BRS 2	improv\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
2	BRS 2	improv\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
3	BRS 18	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:47	
4	BRS 1	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with processing with system\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:01	

Type	Hits	Search Text	DBS	Time Stamp	Comments
5	BRS 3	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
6	BRS 8	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
7	BRS 0	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and (calculate\$3 or comput\$3) with error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:03	

Type	Hits	Search Text	DBs	Time Stamp	Comments
8	5	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and (calculat\$3 or comput\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:29	
9	3	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and calculat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:30	
10	3	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and calculat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	

Type	Hits	Search Text	DBs	Time Stamp	Comments
11	BRS 4	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	
12	BRS 4	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and accurac\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:32	
13	BRS 21	tim\$3 with edge\$1 same accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:45	

Type	Hits	Search Text	DBs	Time Stamp	Comments
14	BRS 13	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:51	
15	BRS 9	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	
16	BRS 10	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	

Type	Hits	Search Text	DBs	Time Stamp	Comments
17	BRS 1	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US - PGPUB; USPAT; EPO; JPO; DERWENT; IBM _ TDB	2006/03/27 10:53	
18	BRS 12	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US - PGPUB; USPAT; EPO; JPO; DERWENT; IBM _ TDB	2006/03/27 11:02	

Type	Hits	Search Text	DBs	Time Stamp	Comments
19	4	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and instruct\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
20	5	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

Type	Hits	Search Text	DBs	Time Stamp	Comments
21	BRS 12	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
22	BRS 15	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:04	

Type	Hits	Search Text	DBs	Time Stamp	Comments
23	0	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digits\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:05	
24	4	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digits\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

Type	Hits	Search Text	DBs	Time Stamp	Comments
		(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	
26	4	(calibrat\$3 or adjust\$3) with tim\$3 with edg\$3 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:08	

Type	Hits	Search Text	DBs	Time Stamp	Comments
27	28	(calibrat\$3 or adjust\$3) with tim\$3 with edg\$3 and test\$3 with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:08	

Type	Hits	Search Text	DBs	Time Stamp	Comments
		(calibrat\$3 or adjust\$3) with tim\$3 with edg\$3 and test\$3 with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3 and computer\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:09	
28	20	702/57,69.ccls. or 714/724,742,744.ccls. or 324/158.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:10	
29	9747	improv\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
30	2				

Type	Hits	Search Text	DBs	Time Stamp	Comments
31	BRS 2	improv\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:33	
32	BRS 19	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:49	
33	BRS 2	(expected or desired) with tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:49	
34	BRS 2	"20060036387"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 09:58	
35	BRS 1	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with processing with system\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:01	

Type	Hits	Search Text	DBs	Time Stamp	Comments
36	BRS 3	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or digital with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
37	BRS 8	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:02	
38	BRS 0	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and (calculat\$3 or comput\$3) with error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:11	

Type	Hits	Search Text	DBs	Time Stamp	Comments
39	2	(compar\$4 or differen\$2) with tim\$3 with edge\$1 with signal\$1 with (threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) and (DUT or devices\$1 adj. under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digits\$2) with process\$3) and (calculat\$3 or comput\$3) with.error\$1 tim\$3 with edge\$1 with signal\$1 with (threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) same (DUT or device\$1 adj under adj test) with (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:15	
40	1		US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:17	

Type	Hits	Search Text	DBs	Time Stamp	Comments
41	BRS 26	tim\$3 with edge\$1 with signal\$1 with (threshold\$1 or reference\$1 or expected or desired or predetermined or predefined) same (DUT or predefined) same (DUT or device\$1 adj under adj test) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:20	
42	BRS 1	tim\$3 with occurrence\$1 with edge\$1 with signals\$1 with (DUT or device\$1 adj under adj test) (threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) with tim\$3 with point\$1 with edge\$1 with signals\$1 same (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:21	

Type	Hits	Search Text	DBs	Time Stamp	Comments
44	39	(threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) with tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:27	
45	2	(determin\$3 or calculat\$3 or computing or comput or computa) with (threshold\$1 or reference\$1 or expected or desired or predetermined or preset\$4 or predefined) with tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:27	
46	5	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and (calculat\$3 or comput\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:29	

Type	Hits	Search Text	DBs	Time Stamp	Comments
47	BRS 3	tim\$3 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and calculat\$3	US_PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:30	
48	BRS 3	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and calculat\$3	US_PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	
49	BRS 4	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and error\$1	US_PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:31	

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50	BRS 4	tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and accurac\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:32	
51	BRS 23	tim\$3 with edge\$1 same accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:46	
52	BRS 40	tim\$3 with edge\$1 same occur\$6 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:49	

Type	Hits	Search Text	DBs	Time Stamp	Comments
53	BRS 24	tim\$3 with edge\$1 with occur\$6 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	
54	BRS 0	compar\$4 with tim\$3 with edge\$1 with occur\$6 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	
55	BRS 4	compar\$4 same tim\$3 with edge\$1 with occur\$6 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:50	

Type	Hits	Search Text	DBs	Time Stamp	Comments
56	BRS 14	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:51	
57	BRS 10	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	
58	BRS 11	tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:52	

Type	Hits	Search Text	DBS	Time Stamp	Comments
59	2	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:58	
60	2	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 with accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 10:59	

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61	BRS 13	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
62	BRS 5	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and instruct\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

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63	BRS 13	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or devices\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:02	
64	BRS 5	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or devices\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and instruct\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

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65	BRS 6	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
66	BRS 6	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and error\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	

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67	BRS 13	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:03	
68	BRS 13	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 and accurac\$3 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:04	

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69	BRS 17	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 and (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:04	
70	BRS 0	(calibrat\$3 or adjust\$3) with tim\$3 with edge\$1 same (DUT or device\$1 adj under adj test) with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

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71	BRS 5	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	
72	BRS 5	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edge\$1 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:07	

Type	Hits	Search Text	DBs	Time Stamp	Comments
73	BRS 5	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edg\$3 same (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digits2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or thresholdd\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:08	

Type	Hits	Search Text	DBs	Time Stamp	Comments
74	BRS 32	(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edg\$3 and test\$3 with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:09	

Type	Hits	Search Text	DBs	Time Stamp	Comments
		(calibrat\$3 or adjust\$3 or compensat\$3) with tim\$3 with edg\$3 and test\$3 with (integrated adj circuit\$1 or IC\$1) and (DPS or (data or digit\$2) with process\$3) and cycle\$1 with tim\$3 and clock\$1 and (DUT or device\$1 adj under adj test) and (reference\$1 or threshold\$1 or desired or expected or predefined or predetermined or preset\$4) with tim\$3 and computer\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:09	
76	BRS 18	(702/57, 69.cc1s. or 714/724, 742, 744.cc1s. or 324/158.1.cc1s.) and tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:18	

Type	Hits	Search Text	DBs	Time Stamp	Comments
		(702/57, 69.cccls. or 714/724, 742, 744.cccls. or 324/158.1.cccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test)	US-PPGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:13	
77	6	(702/57, 69.cccls. or 714/724, 742, 744.cccls. or 324/158.1.cccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 same (DUT or device\$1 adj under adj test)	US-PPGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:13	
78	2	tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PPGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:13	
79	112	(702/57, 69, 117.cccls. or 714/724, 742, 744.cccls. or 324/158.1.cccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PPGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:17	
80	23	(702/57, 69, 117.cccls. or 714/724, 742, 744.cccls. or 324/158.1.cccls.) and tim\$3 with point\$1 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PPGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:24	

Type	Hits	Search Text	DBs	Time Stamp	Comments
81	BRS 86	("702" / \$.ccls. or "714" / \$.ccls. or "324" / \$.ccls.) and tim\$3 with points\$1 with edges\$1 with signals\$1 and (DUT or device\$1 adj under adj test) (702/57, 69, 117, 119.cccls. or 714/700, 718, 724, 736, 742, 74 3, 744, 815.cccls. or 324/158.1.cccls.) and tim\$3 with points\$1 with edges\$1 with signals\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:19	
82	BRS 42	(702/57, 69, 117, 119.cccls. or 714/700, 718, 724, 736, 742, 74 3, 744, 815.cccls. or 324/158.1.cccls.) and tim\$3 with edges\$1 with signals\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:25	

Type	Hits	Search Text	DBs	Time Stamp	Comments
84	BRS 116	(702/57, 69, 117, 119.cc1s. or 714/700, 718, 724, 736, 742, 74 3, 744, 815.cc1s. or 324/158.1.cc1s.) and tim\$3 with edge\$1 with signals\$1 same (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:25	
85	BRS 53	(702/57, 69, 117, 119.cc1s. or 714/700, 718, 724, 736, 742, 74 3, 744, 815.cc1s. or 324/158.1.cc1s.) and tim\$3 with edge\$1 with signals\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:27	
86	BRS 9	(702/57, 69, 117, 119.cc1s. or 714/700, 718, 724, 736, 742, 74 3, 744, 815.cc1s. or 324/158.1.cc1s.) and tim\$3 with edge\$1 with signals\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 11:29	

Type	Hits	Search Text	DBs	Time Stamp	Comments
		(count\$3 or occur\$6 or number\$1) with tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 12:28	
87	BRS 12	(compar\$4 or differen\$2) with (count\$3 or occur\$6 or number\$1) with tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 11:30	
88	BRS 4	(702/57, 69, 117, 119.cc1s. or 714/700, 718, 724, 736, 742, 743, 744, 815.cc1s. or 324/158.1.cc1s.) and tim\$3 with edge\$1 with signal\$1 and (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 11:31	
89	BRS 43	cycles\$ with signal\$1 with tester\$1 with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:46	
90	BRS 170	generat\$3 with cycles\$ with signal\$1 with tester\$1 with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:47	
91	BRS 70				

Type	Hits	Search Text	DBs	Time Stamp	Comments
92	BRS 6	generat\$3 with cycle\$ with edge with signal\$1 with tester\$1 with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 11:49	
93	BRS 7	generat\$3 with cycle\$ with edge with signal\$1 with ((DUT or device adj under adj test\$3) or tester\$1) with cycle\$1 with tim\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 11:50	
94	BRS 12	(count\$3 or occur\$6 or number\$1) with tim\$3 with (peak\$1 or edge\$1) with signal\$1 with (DUT or device\$1 adj under adj test)	US-PGPUB	2006/03/27 12:28	
95	BRS 0	compar44 with expected with tim\$3 with edge with signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 12:55	
96	BRS 40	compar\$4 with expected with tim\$3 with edge with signal\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM TDB	2006/03/27 12:55	

Type	Hits	Search Text	DBs	Time Stamp	Comments
		compar\$4 with expected with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
97	2	compar\$4 with (desired or expected) with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
98	2	(differen\$2 or compar\$4) with (desired or expected) with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
99	2	(differen\$2 or compar\$4) with (desired or expected) with tim\$3 with edge with signal\$1 same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 12:56	
100	10	tim\$3 with edge\$1 with signals\$1 with (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:08	
101	126	tim\$3 with edge\$1 with signals\$1 with (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:08	

Type	Hits	Search Text	DBs	Time Stamp	Comments
102	BRS 14	(adjust\$3 or calibrat\$3 or compensat\$3) with tim\$3 with edge\$1 with signal\$1 with (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:14	
103	BRS 0	(adjust\$3 or calibrat\$3 or compensat\$3) with tim\$3 with edge\$1 with signal\$1 with actual same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:15	
104	BRS 0	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with ((expected or desired) adj tim\$3) same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:16	
105	BRS 0	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with (expected or desired) same (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:16	

Type	Hits	Search Text	DBs	Time Stamp	Comments
106	BRS 1	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with (expected or desired) and (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:17	
107	BRS 6	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 with (expected or desired or predefined or predetermined or preset\$4 or reference\$1 or threshold\$1) and (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:21	
108	BRS 12	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (expected or desired or predefined or predetermined or preset\$4 or reference\$1 or threshold\$1) with tim\$3 with edge\$1 and (DUT or device\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 13:23	

Type	Hits	Search Text	DBs	Time Stamp	Comments
109	BRS 9	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (expected or desired or predefined or predetermined or preset\$4 or references\$1 or threshold\$1) with tim\$3 with edges\$1 and cycle\$1 with tim\$3 and (DUT or devices\$1 adj under adj test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 14:31	
110	BRS 3	(adjust\$3 or calibrat\$3 or compensat\$3) with (tim\$3 adj edge\$1) with signal\$1 and (tester\$1 or DUT or (devices\$1 adj under adj test\$3)) with cycle\$1 with time\$1	US_PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	2006/03/27 14:33	

	U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
1			US 2006004982	20060309	17	Method and apparatus for remotely buffering test channels	324/158.1		324/158.1
2	X		US 2006003172	20060209	15	Method and apparatus for measuring digital timing paths by setting a scan mode of sequential storage elements	714/724		714/724
3	X		US 2006001035	20060112	21	Method and apparatus for calibrating and/or deskewing communications channels	714/700	455/67.16	714/700
4	X		US 2005026769	20051201		Measurement instrument and measurement method	702/57		702/57
5	X		US 2005024660	20051103	12	Pin coupler for an integrated circuit tester	714/742		714/742
6	X		US 2005024660	20051103		Method and apparatus to measure and display data dependent eye diagrams	714/724		714/724

	U 1	Document ID.	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval 1	Retrieval Classif
7	X	US 2005022531 4 A1	20051013		Method of measuring duty cycle	324 / 158 . 1		324 / 158 . 1	
8	X	US 2005019335 5 A1	20050901 19		Source synchronous timing extraction, cyclization and sampling	716 / 6	703 / 19; 714 / 724	714 / 724	
9	X	US 2005016033 1 A1	20050721		PICA system timing measurement and calibration	714 / 700		714 / 700	
10	X	US 2005009742 0 A1	20050505 26		Apparatus for jitter testing an IC	714 / 742		714 / 742	
11	X	US 2005008816 7 A1	20050428		Isolation buffers with controlled equal time delays	324 / 158 . 1		324 / 158 . 1	
12	X	US 2005008058 0 A1	20050414 27		Device for testing lsi to be measured, jitter analyzer, and phase difference detector	702 / 117		702 / 117	
13	X	US 2005005041 1 A1	20050303		Pre-stored digital word generator	714 / 724		714 / 724	

	U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
		X	US 2005003861 5 A1	20050217		Qualification signal measurement, trigger, and/or display system	702/69		702/69
14		X	US 2005003404 4 A1	20050210	25	Semiconductor test device and timing measurement method	714/742		714/742
15		X	US 2005002806 2 A1	20050203		Test method and apparatus for high-speed semiconductor memory devices	714/736		714/736
16		X	US 2005002208 8 A1	20050127		Semiconductor tester	714/744		714/744
17		X	US 2005002208 1 A1	20050127	42	Test systems and methods with compensation techniques	714/724		714/724
18		X	US 2005002208 0 A1	20050127	43	Systems and methods associated with test equipment	714/724		714/724
19		X	US 2004026049 2 A1	20041223	9	Direct jitter analysis of binary sampled data	702/69		702/69
20		X							

U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
21	X	US 2004015326	20040805	7 A1	System and method of testing a transceiver	702/69		702/69
22	X	US 2004012260	20040624	7 A1	System and method of measuring a signal propagation delay	702/69		702/69
23	X	US 2004007874	20040422	0 A1	Memory tester uses arbitrary dynamic mappings to serialize vectors into transmitted sub-vectors and deserialize received sub-vectors into vectors	714/718		714/718
24	X	US 2004006476	20040401	5 A1	Deskewed differential detector employing analog-to-digital converter	714/700	714/724	714/700; 714/724
25	X	US 2004005151	20040318	8 A1	High speed tester with narrow output pulses	324/158.1		324/158.1
26	X	US 2004000332	20040101	8 A1	Instrument initiated communication for automatic test equipment	714/724		714/724

	U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval 1	Classif
27	X		US 2003023360 4 A1	20031218		Memory device test system and method	714/718		714/718	
28	X		US 2003022946 6 A1	20031211		Test method and apparatus for source synchronous signals	702/117		702/117	
29	X		US 2003015868 7 A1	20030821	11	Composite eye diagrams	702/117		702/117	
30	X		US 2003012653 0 A1	20030703	13	Time shift circuit for functional and AC parametric test	714/724		714/724	
31	X		US 2003011712 9 A1	20030626	7	Low-cost tester interface module	324/158.1	324/765	324/158.1	
32	X		US 2003011042 7 A1	20030612		Semiconductor test system storing pin calibration data in non-volatile memory	714/724		714/724	
33	X	X	US 2003002883 2 A1	20030206	18	Driver for integrated circuit chip tester	714/700		714/700	
34	X		US 2003000537 5 A1	20030102		Algorithmically programmable memory tester with test sites operating in a slave mode	714/724		714/724	

Retrieval Classif	Current XRef	Current OR	Title	Page s	Issue Date	Document ID	U 1
324 / 158 . 1	324 / 158 . 1	324 / 158 . 1	Method for manufacturing smart card and identification devices and the like	324 / 158 .1	US 2002018600 4 A1	X	35
714 / 724	714 / 724	714 / 724	Method for testing semiconductor chips and semiconductor device	714 / 724	US 2002018458 1 A1	X	36
714 / 724	714 / 724	714 / 724	Differential receiver architecture	714 / 724	US 2002017000 6 A1	X	37
714 / 724	714 / 724	714 / 724	Circuitry for and system and substrate with circuitry for aligning output signals in massively parallel testers and other electronic devices	714 / 724	US 2002015243 7 A1	X	38
324 / 158 . 1	324 / 158 . 1	324 / 158 . 1	Method and apparatus for socket calibration of integrated circuit testers	324 / 158 .1	US 2002013535 7 A1	X	39

	U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
40	X		US 2002012587	20020912		High-frequency tester for semiconductor devices	324/158.1		324/158.1
41	X		US 2002007776	20020620		Automatic tester having separate coarse and precise timing modules	702/120	702/117	702/117
42	X		US 2002004289	20020411		Test interface for verification of high speed embedded synchronous dynamic random access memory (SDRAM) circuitry	714/744	365/192	714/744
43	X		US 2001001046	20010802		Carrier identification system, carrier identification method and storage media	324/158.1		324/158.1